

# INFORMATION DISCLOSURE CITATION IN AN APPLICATION

ATTY. DOCKET NO.  
**4653/PDC/WF/LE**

SERIAL NO.  
**unassign d**

(PTO-1449)

APPLICANT  
**Daniel I SOME, et al.**

FILING DATE  
**unassigned**

GROUP  
**unassigned**

# U.S. PATENT DOCUMENTS

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No

**OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)**



**EXAMINER**

## Horn Song

**DATE CONSIDERED**

3-4-03

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

INFORMATION DISCLOSURE CITATION IN AN APPLICATION  (PTO-1449)			ATTY. DOCKET NO. <b>49959-145</b>	SERIAL NO. <b>09/784,626</b>		
			APPLICANT <b>Dani I ISOME, et al.</b>			
			FILING DATE <b>February 14, 2001</b>	GROUP <b>2878</b>		
<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
HKS	6,067,154	05/23/00	Hossain et al.	356	237.2	10/23/98
HKS	4,692,690	09/08/87	Hara et al.	327	73 PC	12/24/84
<b>FOREIGN PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	RECEIVED OCT - 7 2002 TECHNOLOGY CENTER 2800
Translation Yes No						
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>						
HKS	PCT International Search Report dated September 27, 2002.					
	"APPLICATION OF ROOM TEMPERATURE PHOTOLUMINESCENCE FOR THE CHARACTERIZATION OF IMPURITIES AND DEFECTS IN SILICON", V. Higgs et al., Electrochemical Society Proceedings, September 13, 1999, Volume 99-16, pp. 21-37.					
EXAMINER	Hoon Song		DATE CONSIDERED			3-4-03

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